

PolarHV[™] HiPerFET Power MOSFET

IXFH 36N60P IXFK 36N60P IXFT 36N60P

 $V_{DSS} = 600 V$ $I_{D25} = 36 A$ $R_{DS(on)} \le 190 m\Omega$ $t_{rr} \le 200 ns$

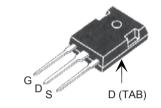
N-Channel Enhancement Mode Avalanche Rated Fast Intrinsic Diode



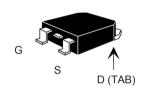
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Symbol	Test Conditions		Maxin	num Ra	tings
V _{DSS}	T _J = 25° C to 150° C		6	600	V
\mathbf{V}_{DGR}	$T_{_{ m J}}$ = 25° C to 150° C; $R_{_{ m GS}}$ = 1 M Ω		(00	V
V _{GSS}	Continuous		=	<u>⊦</u> 30	V
V _{GSM}	Transient		Ξ	<u>⊦</u> 40	V
I _{D25}	T _C =25°C			36	Α
I _{DM}	$T_{_{\rm C}}$ = 25° C, pulse width limited by $T_{_{\rm JM}}$			80	Α
I _{AR}	T _c = 25° C			36	Α
\mathbf{E}_{AR}	T _C = 25° C			50	mJ
E _{AS}	T _C = 25° C			1.5	J
dv/dt	$I_{S} \leq I_{DM}$, di/dt ≤ 100 A/ μ s, $V_{DD} \leq V_{DSS}$, $T_{J} \leq 150^{\circ}$ C, $R_{G} = 4$ Ω			20	V/ns
$\overline{\mathbf{P}_{\scriptscriptstyle \mathrm{D}}}$	T _C =25°C		(650	W
T _J T _{JM} T _{stg}			55 + ²	150	℃ ℃ ℃
M _d	Mounting torque (TO-247 & TO-264)			/10 Nm	
Weight	TO-247 TO-268 TO-264			6 5 10	g g g
T _L	1.6 mm (0.062 in.) from case for 10 s Plastic body for 10 s			300 260	°C °C
Symbol Test Conditions (T _J = 25° C, unless otherwise specified)			aracter Typ.	istic Va Max	
BV _{DSS}	V _{GS} = 0 V, I _D = 250 μA	600			V
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Symbol $(T_J = 25^{\circ} C_s)$	Test Conditions unless otherwise specified)		Ch Min.	_	istic Va Max	
BV _{DSS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		600			V
V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 4 \text{ mA}$		3.0		5.0	V
I _{GSS}	$V_{GS} = \pm 30 V_{DC}, V_{DS} = 0$				±200	nA
I _{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 V$	T _J = 125° C			100 1000	μA μA
R _{DS(on)}	V_{GS} = 10 V, I_{D} = 0.5 I_{D25} Pulse test, t ≤300 µs, duty	cycle d ≤ 2 %			190	mΩ

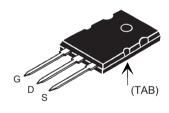
TO-247 (IXFH)



TO-268 (IXFT) Case Style



TO-264 AA (IXFK)



G = Gate D = Drain S = Source Tab = Drain

Features

- ¹ International standard packages
- ¹ Fast recovery diode
- Unclamped Inductive Switching (UIS) rated
- ¹ Low package inductance
 - easy to drive and to protect

Advantages

- Easy to mount
- Space savings
- High power density

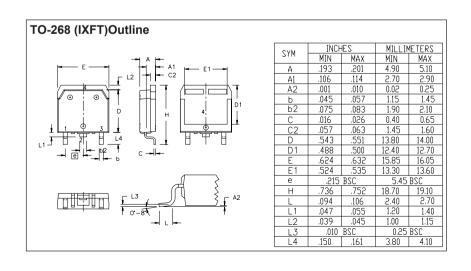


Test Conditions Characteristic Values Symbol (T₁ = 25° C, unless otherwise specified) Min. Typ. | Max. 25 39 S $V_{DS} = 20 \text{ V}; I_{D} = 0.5 I_{D25}, \text{ pulse test}$ g_{fs} $\mathbf{C}_{\mathrm{iss}}$ рF 5800 $V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$ 570 pF C_{rss} 30 рF $\mathbf{t}_{\text{d(on)}}$ 30 ns $V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \text{ I}_{D25}$ t, 25 ns $R_c = 2 \Omega (External)$ 80 $\mathbf{t}_{\mathsf{d(off)}}$ ns 22 $t_{_{\rm f}}$ ns $\mathbf{Q}_{\mathrm{g(on)}}$ 102 nC \mathbf{Q}_{gs} $V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \text{ V}_{DSS}, I_{D} = 0.5 \text{ I}_{D25}$ 34 nC \mathbf{Q}_{gd} 36 nC $\mathbf{R}_{\mathrm{thJC}}$ 0.19 ° C/W $\mathbf{R}_{\mathrm{thCS}}$ TO-247 0.21 °C/W $\mathbf{R}_{\mathrm{thCS}}^{\mathrm{th}}$ TO-264 0.15 °C/W

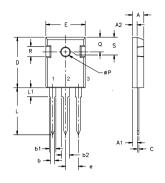
Source-Drain Diode

Characteristic Values (T, = 25°C, unless otherwise specified)

Symbo	I Test Conditions Min.	Тур.	Max.	
I _s	V _{GS} = 0 V		36	A
I _{sm}	Repetitive		80	Α
V _{SD}	$I_F = I_S$, $V_{GS} = 0 \text{ V}$, Pulse test, t \leq 300 μ s, duty cycle d \leq 2 %		1.5	V
t _{rr}	I _F = 25A, -di/dt = 100 A/μs		200	ns
\mathbf{Q}_{RM}	$V_{R} = 100V$	0.8 6.0		μC Α

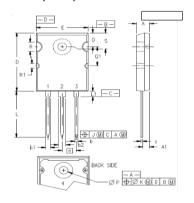


TO-247 AD (IXFH) Outline



Dim.	Millimeter		Inc	Inches		
	Min.	Max.	Min.	Max.		
Α	4.7	5.3	.185	.209		
A,	2.2	2.54	.087	.102		
A ₂	2.2	2.6	.059	.098		
b	1.0	1.4	.040	.055		
b ₁	1.65	2.13	.065	.084		
b ₂	2.87	3.12	.113	.123		
С	.4	.8	.016	.031		
D	20.80	21.46	.819	.845		
E	15.75	16.26	.610	.640		
е	5.20	5.72	0.205	0.225		
L	19.81	20.32	.780	.800		
L1		4.50		.177		
ØP	3.55	3.65	.140	.144		
Q	5.89	6.40	0.232	0.252		
R	4.32	5.49	.170	.216		
S	6.15	BSC	242	BSC		

TO-264 (IXFK) Outline



1 - GATE 2, 4 - DRAIN (COLLECTOR) 3 - SOURCE (EMITTER)

CVAL	INCH	NCHES MILLIMETI		ETERS	
SYM	MIN	MAX	MIN	MAX	
А	.185	.209	4.70	5.31	
A1	.102	.118	2.59	3.00	
ь	.037	.055	0.94	1.40	
b1	.087	.102	2.21	2.59	
b2	.110	.126	2.79	3.20	
С	.017	.029	0.43	0.74	
D	1.007	1.047	25.58	26.59	
E	.760	.799	19.30	20.29	
е	.215	.215BSC 5.4		6 BSC	
J	.000	.010	0.00	0.25	
K	.000	.010	0.00	0.25	
L	.779	.842	19.79	21.39	
L1	.087	.102	2.21	2.59	
ØΡ	.122	.138	3.10	3.51	
Q	.240	.256	6.10	6.50	
Q1	.330	.346	8.38	8.79	
ØR	.155	.187	3.94	4.75	
ØR1	.085	.093	2.16	2.36	
S	.243	.253	6.17	6.43	
	,240	.233	0.17	0.40	

IXYS reserves the right to change limits, test conditions, and dimensions.



Fig. 1. Output Characteristics

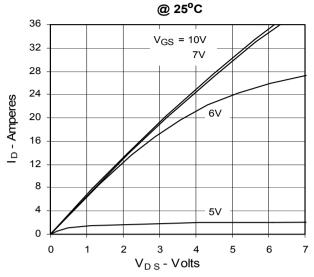


Fig. 3. Output Characteristics

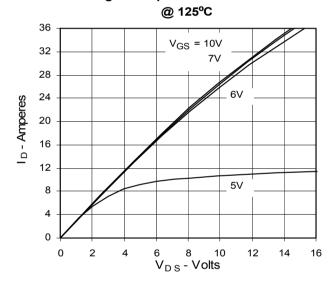


Fig. 5. R_{DS(on)} Normalized to

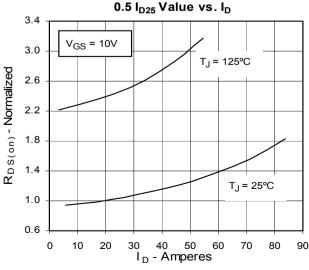


Fig. 2. Extended Output Characteristics @ 25°C

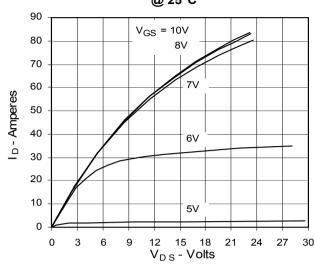


Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Junction Temperature

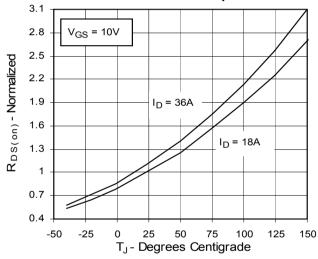


Fig. 6. Drain Current vs. Case

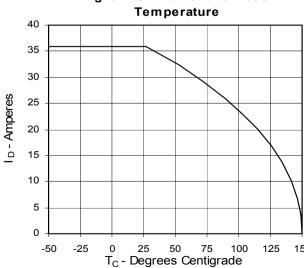




Fig. 7. Input Admittance

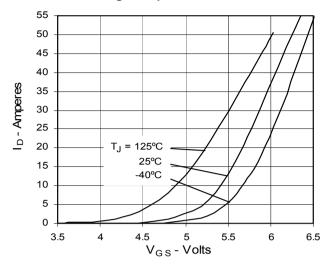


Fig. 9. Source Current vs. Source-To-Drain Voltage

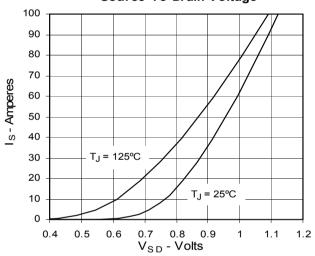


Fig. 11. Capacitance

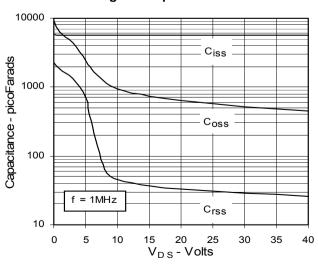


Fig. 8. Transconductance

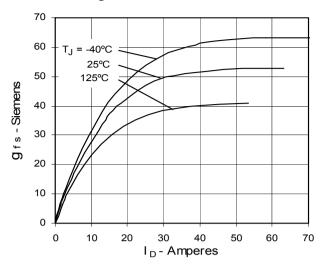


Fig. 10. Gate Charge

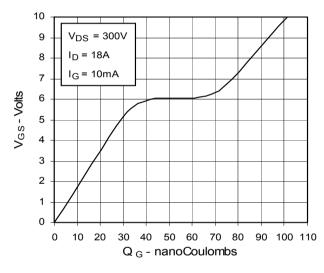
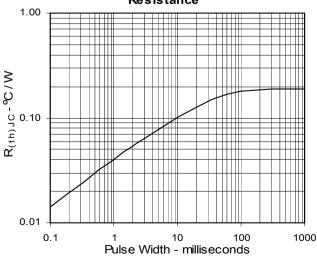


Fig. 12. Maximum Transient Thermal Resistance



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